

First Named Inventor	: Joël Chatal	Group Art Unit: Examiner:
Appln. No.	:	
Filed	: July 9, 2003	
Title	: REFERENCE VOLTAGE SOURCE, TEMPERATURE SENSOR, TEMPERATURE THRESHOLD DETECTOR, CHIP AND CORRESPONDING SYSTEM	
Docket No.	: A815.312-0002	

INFORMATION DISCLOSURE STATEMENT

Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

The enclosed PTO Form-1449 lists patents and publications submitted pursuant to 37 C.F.R. 1.97. Copies of the patents or publications are enclosed as necessary.

Submitted herewith is a copy (with English translation as appropriate) of an Official Search Report of the French Patent Office in counterpart foreign Application No. FR 02 08650 filed July 9, 2002.

TIME OF FILING

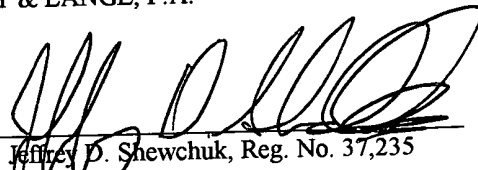
The Information Disclosure Statement is being filed:

1. ☒ with the application or within three months of the filing date of a national application (other than a continued prosecution application under 37 C.F.R. 1.53(d)) or date of entry into the national stage of an international application or, to the best of the undersigned's knowledge, before the mailing date of a first Office action on the merits or a first office action after the filing of a request for continued examination under 37 C.F.R. 1.114, whichever event occurs last. In accordance with 37 C.F.R. 1.97(b), no certification or fee is required.

Respectfully submitted,

KINNEY & LANGE, P.A.

By: _____

A handwritten signature in black ink, appearing to read 'Jeffrey D. Shewchuk', is written over a horizontal line.

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FORM PTO-1449	Atty. Docket No.: A815.312-0002	Application No.:
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	First Named Inventor: Joël Chatal	
	Filing Date: July 9, 2003	Group Art:

U.S. PATENT DOCUMENTS

Examiner Initials	Document No.	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents
AA	6,239,868	05/29/2001	Jung et al.
AB	6,356,161	03/12/2002	Nolan et al.
AC	6,335,661	01/01/2002	Furman
AD	5,604,427	02/18/1997	Kimura
AE			
AF			
AG			
AH			
AI			
AJ			
AK			

FOREIGN PATENT DOCUMENTS

	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents	Translation Yes No
AL				
AM				
AN				

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AO	
AP	
AQ	

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.